

**Search Notes**

Application/Control No.

10/529,145

Examiner

/Yonel Beaulieu/

Applicant(s)/Patent under  
Reexamination

OHNISHI ET AL.

Art Unit

3661

**SEARCHED**

Class	Subclass	Date	Examiner
701	117-119	5/12/2008	YB
	200		
	213-215		
340	988		
701	209		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Int. Search		5/12/2008	YB

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST+Fwd/Bwd+Int.	5/12/2008	YB